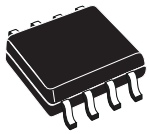
STS8DNF3LL

Dual N-channel 30V - 0.017Ω - 8A SO-8
Low gate charge STripFET™ II Power MOSFET

General features

Type	V_{DSS}	$R_{DS(on)}$	I_D
STS8DNF3LL	30V	<0.020Ω	8A

- Optimal R_{DS}(on) x Qg trade-off @ 4.5V
- Conduction losses reduced
- Switching losses reduced

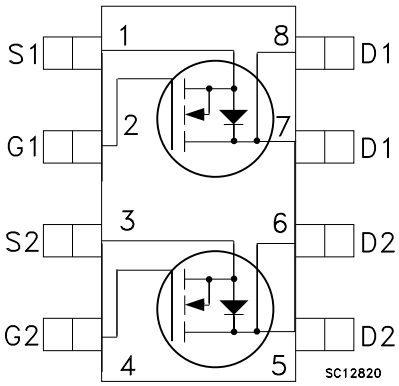


S0-8

Description

This application specific Power MOSFET is the second generation of STMicroelectronics unique "Single Feature Size™" strip-based process. The resulting transistor shows the best trade-off between on-resistance and gate charge. When used as high and low side in buck regulators, it gives the best performance in terms of both conduction and switching losses. This is extremely important for motherboards where fast switching and high efficiency are of paramount importance.

Internal schematic diagram



Applications

- Switching application

Order codes

Part number	Marking	Package	Packaging
STS8DNF3LL	S8DNF3LL	SO-8	Tape & reel

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1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage (v_{gs} = 0)	30	V
V_{GS}	Gate- source voltage	±16	V
I_D	Drain current (continuos) at T_C = 25°C single operating	8	A
I_D	Drain current (continuos) at T_C = 100°C single operating	5	A
I_{DM} (1)	Drain current (pulsed)	32	A
P_{TOT}	Total dissipation at T_C = 25°C dual operating Total dissipation at T_C = 25°C single operating	2 1.6	W W

1. Pulse width limited by safe operating area

Table 2. Thermal data

$R_{thj\text{-}a}$	(1)Thermal resistance junction-ambient single operating Thermal resistance junction-ambient dual operating	78 62.5	°C/W °C/W
T_J	Thermal operating junction-ambient	150	°C
T_{stg}	Storage temperature	-55 to 150	°C

1. Mounted on FR-4 board with 0.5 in^2 pad of Cu.

2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Table 3. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source Breakdown voltage	I_D = 250 µA, V_{GS} = 0	30			V
I_{DSS}	Zero gate voltage Drain current (V_{GS} = 0)	V_{DS} = Max rating V_{DS}=Max rating, T_C=125°C			1 10	µA µA
I_{GSS}	Gate-body leakage current (V_{DS} = 0)	V_{GS} = ± 16V			±100	nA
$V_{GS(th)}$	Gate threshold voltage	V_{DS} = V_{GS}, I_D = 250µA	1			V
$R_{DS(on)}$	Static drain-source on resistance	V_{GS} = 10V, I_D = 4A V_{GS} = 4.5V, I_D = 4A		0.017 0.020	0.020 0.024	Ω Ω

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
g_{fs} (1)	Forward transconductance	V_{DS} = 15V, I_D= 4 A		12.5		S
C_{iss}	Input capacitance	V_{DS} = 25V, f = 1 MHz, V_{GS} = 0		800		pF
C_{oss}	Output capacitance			250		pF
C_{rss}	Reverse transfer capacitance			60		pF
Q_g	Total gate charge	V_{DD} = 15V, I_D = 8A, V_{GS} = 5V (see Figure 14)		12.5	17	nC
Q_{gs}	Gate-source charge			3.2		nC
Q_{gd}	Gate-drain charge			4.5		nC

1. Pulsed: Pulse duration = 300 µs, duty cycle 1.5.

Table 5. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ t_r	Turn-on delay time Rise time	V_{DD}=15 V, I_D=4A, R_G=4.7Ω, V_{GS}= 4.5V (see Figure 13)		18 32		ns ns
$t_{d(off)}$ t_f	Turn-off Delay Time Fall Time	V_{DD}=15 V, I_D=4A, R_G=4.7Ω, V_{GS}= 4.5V (see Figure 13)		21 11		ns ns

Table 6. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
I_{SD}	Source-drain current				8	A
I_{SDM} (1)	Source-drain current (pulsed)				32	A
V_{SD} (2)	Forward on voltage	I_{SD} = 8A, V_{GS} = 0			1.2	V
t_{rr} Q_{rr} I_{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD} = 8A, V_{DD} = 15V di/dt = 100A/µs, T_j = 150°C (see Figure 15)		23 17 1.5		ns nC A

1. Pulse width limited by safe operating area.
2. Pulsed: Pulse duration = 300 µs, duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

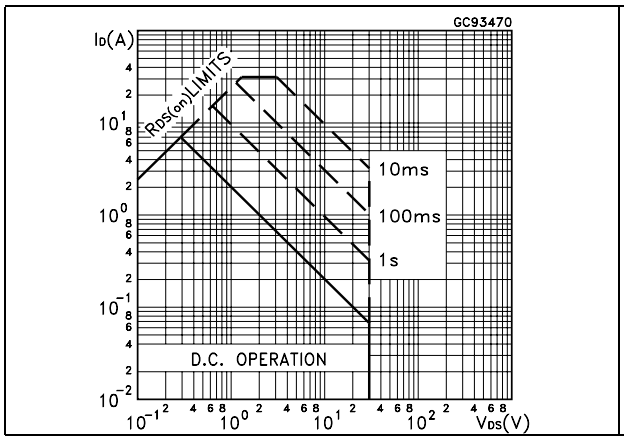


Figure 2. Thermal impedance

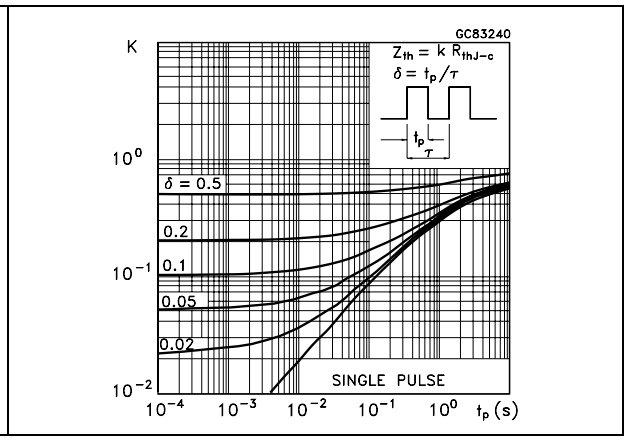


Figure 3. Output characteristics

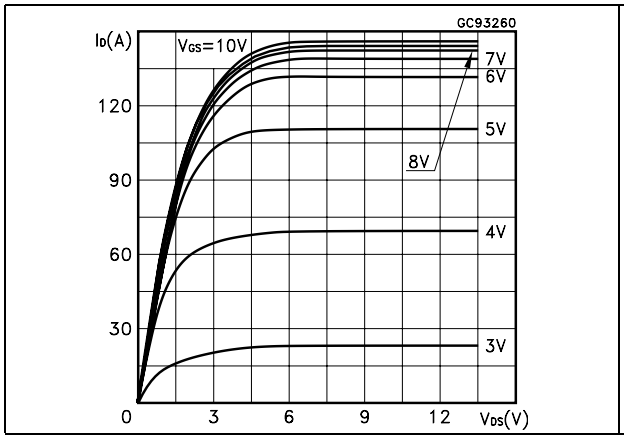


Figure 4. Transfer characteristics

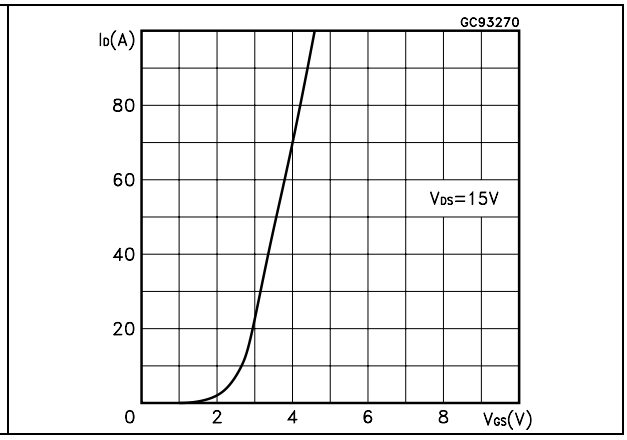


Figure 5. Transconductance

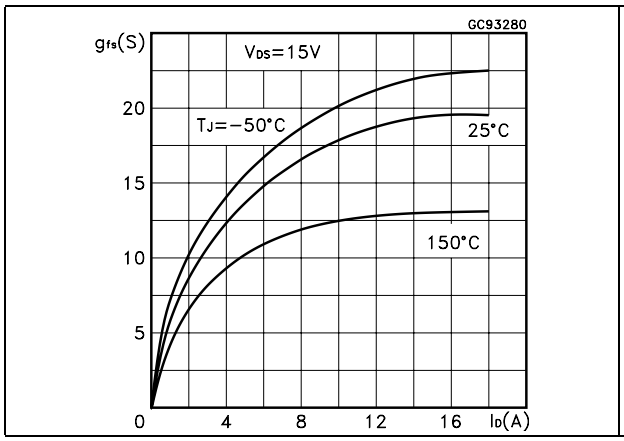


Figure 6. Static drain-source on resistance

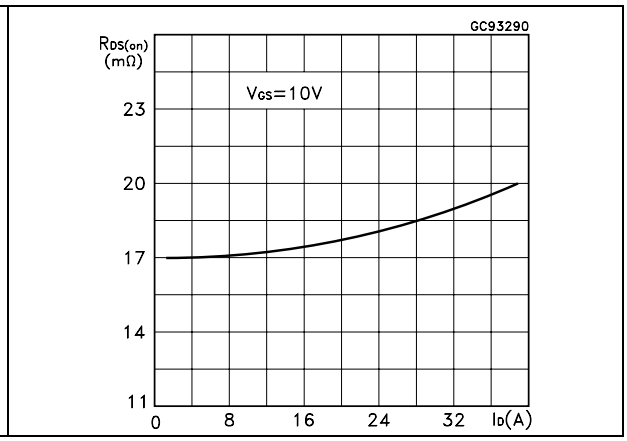


Figure 7. Gate charge vs. gate-source voltage

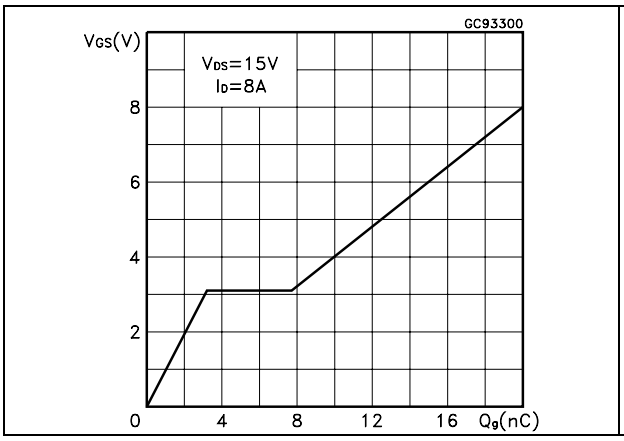


Figure 8. Capacitance variations

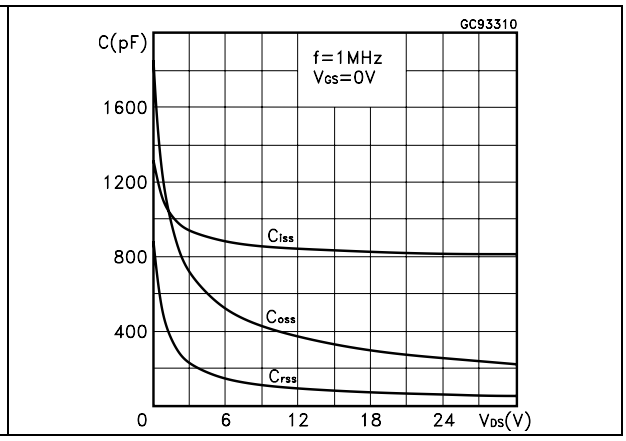


Figure 9. Normalized gate threshold voltage vs. temperature

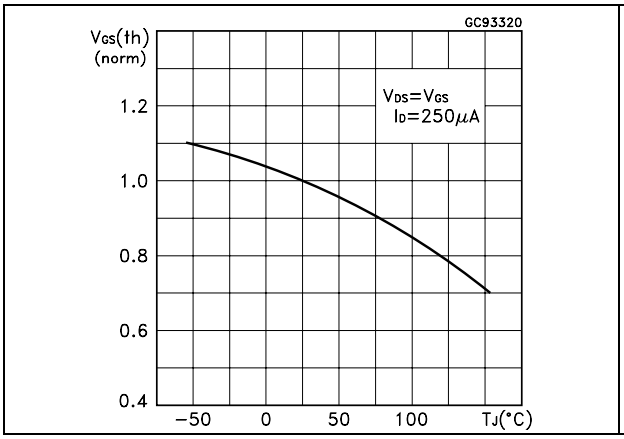


Figure 10. Normalized on resistance vs. temperature

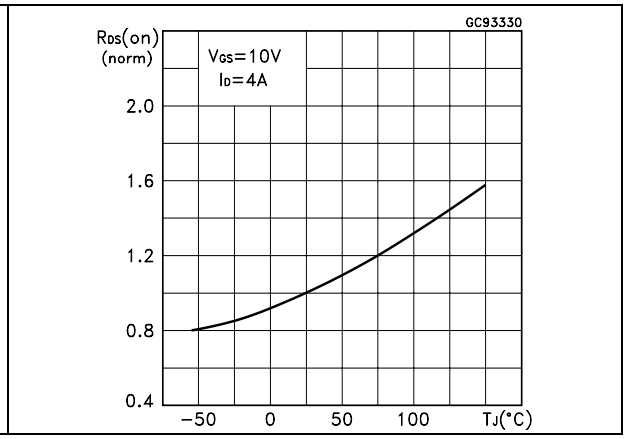


Figure 11. Source-drain diode forward characteristics

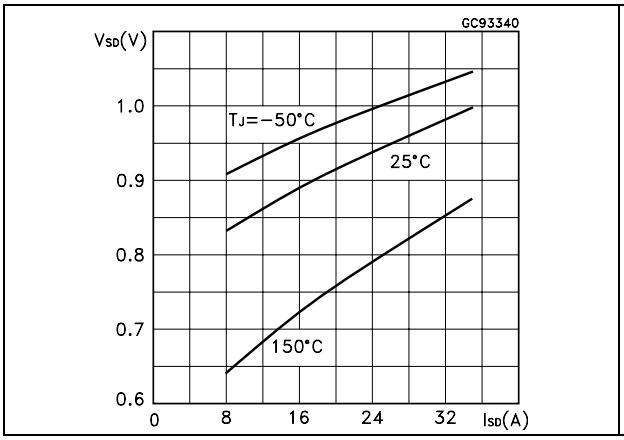
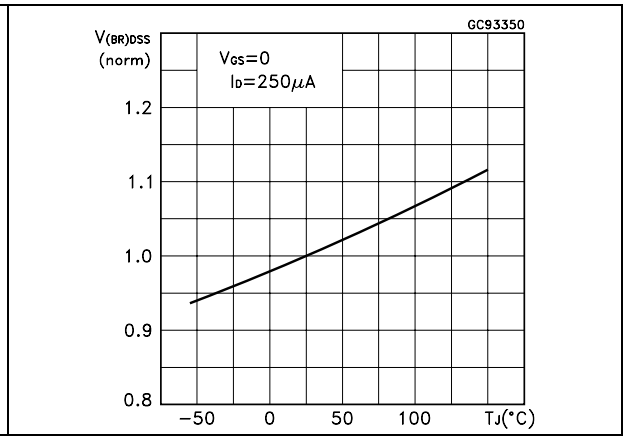


Figure 12. Normalized breakdown voltage vs. temperature



3 Test circuit

Figure 13. Switching times test circuit for resistive load

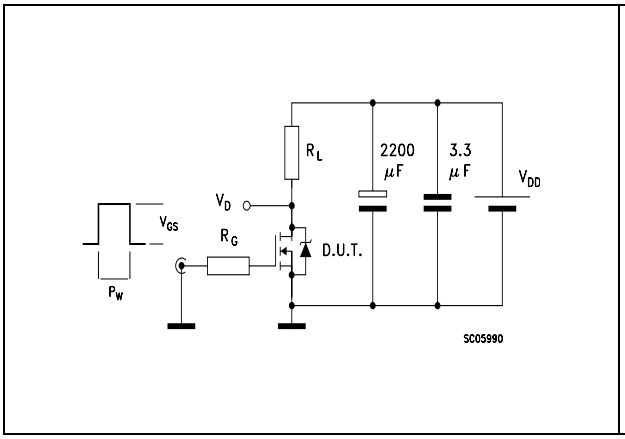


Figure 14. Gate charge test circuit

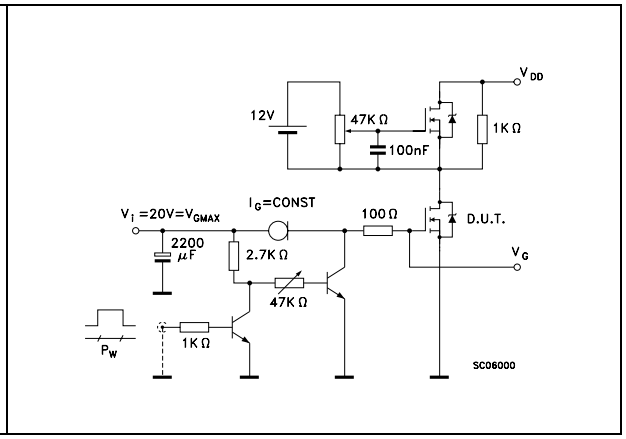


Figure 15. Test circuit for inductive load switching and diode recovery times

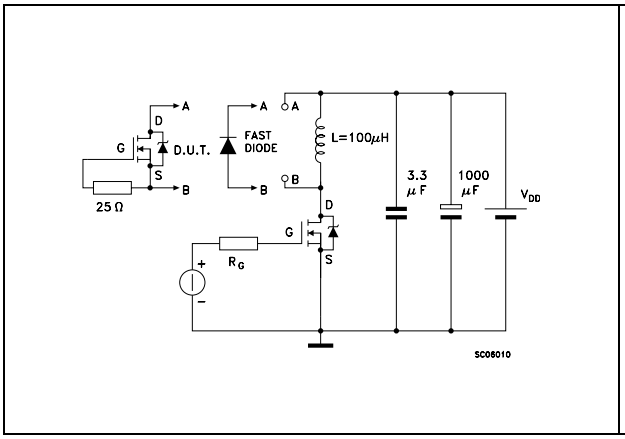


Figure 16. Unclamped Inductive load test circuit

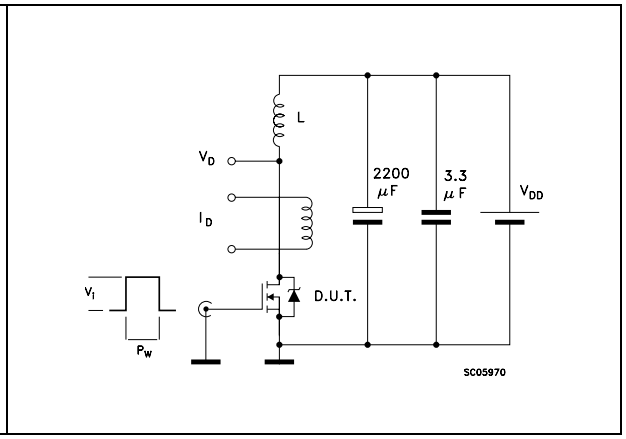


Figure 17. Unclamped inductive waveform

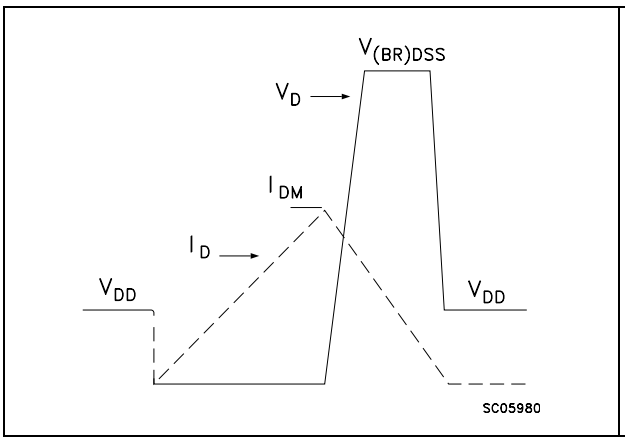
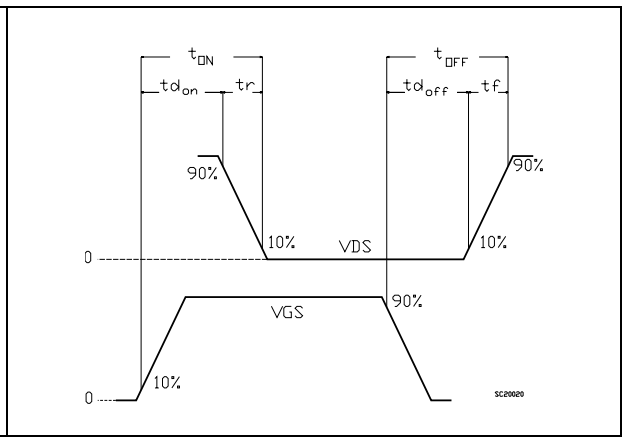


Figure 18. Switching time waveform

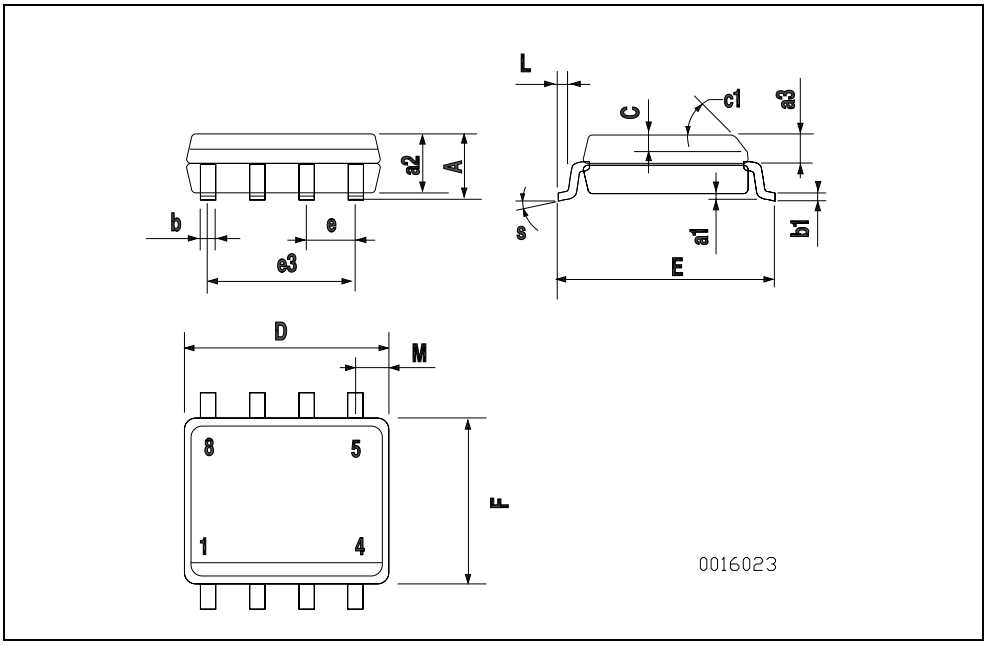


4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at : *www.st.com*

SO-8 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A			1.75			0.068
a1	0.1		0.25	0.003		0.009
a2			1.65			0.064
a3	0.65		0.85	0.025		0.033
b	0.35		0.48	0.013		0.018
b1	0.19		0.25	0.007		0.010
C	0.25		0.5	0.010		0.019
c1	45 (typ.)					
D	4.8		5.0	0.188		0.196
E	5.8		6.2	0.228		0.244
e		1.27			0.050	
e3		3.81			0.150	
F	3.8		4.0	0.14		0.157
L	0.4		1.27	0.015		0.050
M			0.6			0.023
S	8 (max.)					



5 Revision history

Table 7. Revision history

Date	Revision	Changes
11-Sep-2006	8	Complete document
15-Nov-2006	9	The document has been reformatted
30-Jan-2007	10	Typo mistake on *Table 1*.

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